

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Ryosuke MESHII et al.

T. C. Art Unit: 2829

Appl. No.: 10/599,396

Examiner: K. M. Kusumakar

Filed: September 27, 2006

Confirmation No.: 8147

For: SEMICONDUCTOR PHYSICAL QUANTITY SENSOR OF
ELECTROSTATIC CAPACITANCE TYPE AND METHOD FOR
MANUFACTURING THE SAME

COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE

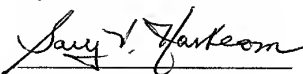
Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop Issue Fee
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In response to the Notice of Allowability, mailed by the U.S. Patent and Trademark Office on June 7, 2010 and to the Statement of Reasons for Allowance attached thereto, Applicants wish to clarify the record with respect to the basis for the patentability of claims in the present application. In this regard, while Applicants do not disagree with the Examiner's indication of allowability, Applicants submit that each of the claims in the present patent application recites a combination of features, and that the basis for patentability of each of these claims is based on the combination of features recited therein.

Should there be any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,
Ryosuke MESHII et al.


for Bruce H. Bernstein
Reg. No. 29,027

August 19, 2010
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